

# Silicon NPN Transistor

## **2SC3046 / C3046**

450V/10A

# DATASHEET

OEM – Fujitsu

Source: Fujitsu Databook 1983

**FUJITSU**  
**MICROELECTRONICS**

**2SC3046**

**SILICON HIGH SPEED RING EMITTER**  
**NPN POWER TRANSISTOR 10 AMP, 450 VOLT**

**ABSOLUTE MAXIMUM RATINGS**

Rating	Symbol	Value	Unit
Collector to Emitter Voltage	$V_{CEO}$	450	V
Collector to Base Voltage	$V_{CBO}$	600	V
Emitter to Base Voltage	$V_{EBO}$	7	V
Collector Current-Continuous	$I_C$	10	A
Collector Current-Pulsed $P_W \leq 10\text{ms}$ , D.R. $\leq 2\%$	$I_{CP}$	20	A
Base Current-Continuous	$I_B$	5	A
Collector Power Dissipation ( $T_C = 25^\circ\text{C}$ )	$P_C$	100	W
Junction Temperature	$T_j$	+175	$^\circ\text{C}$
Storage Temperature Range	$T_{stg}$	-65 ~ +175	$^\circ\text{C}$

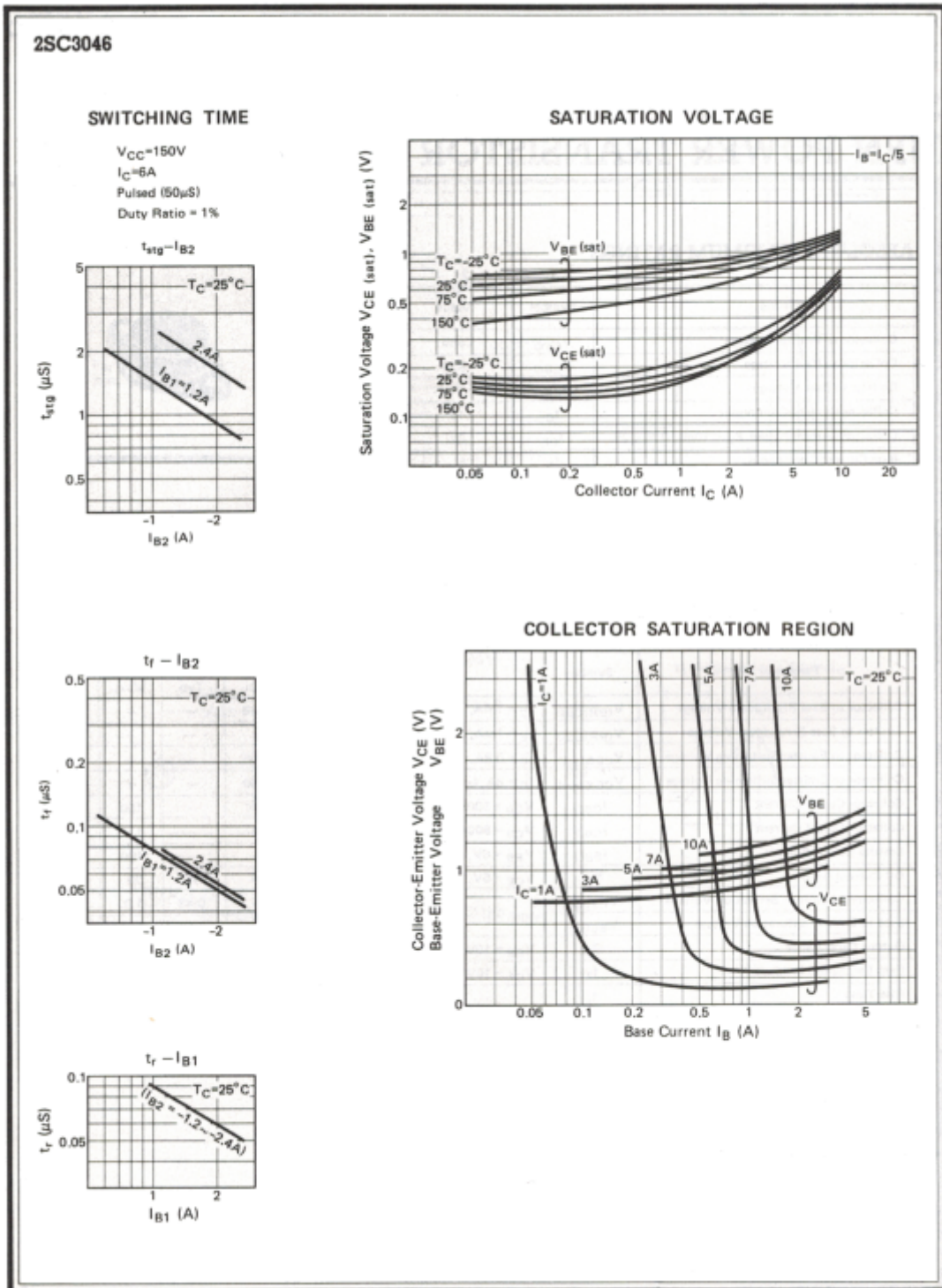


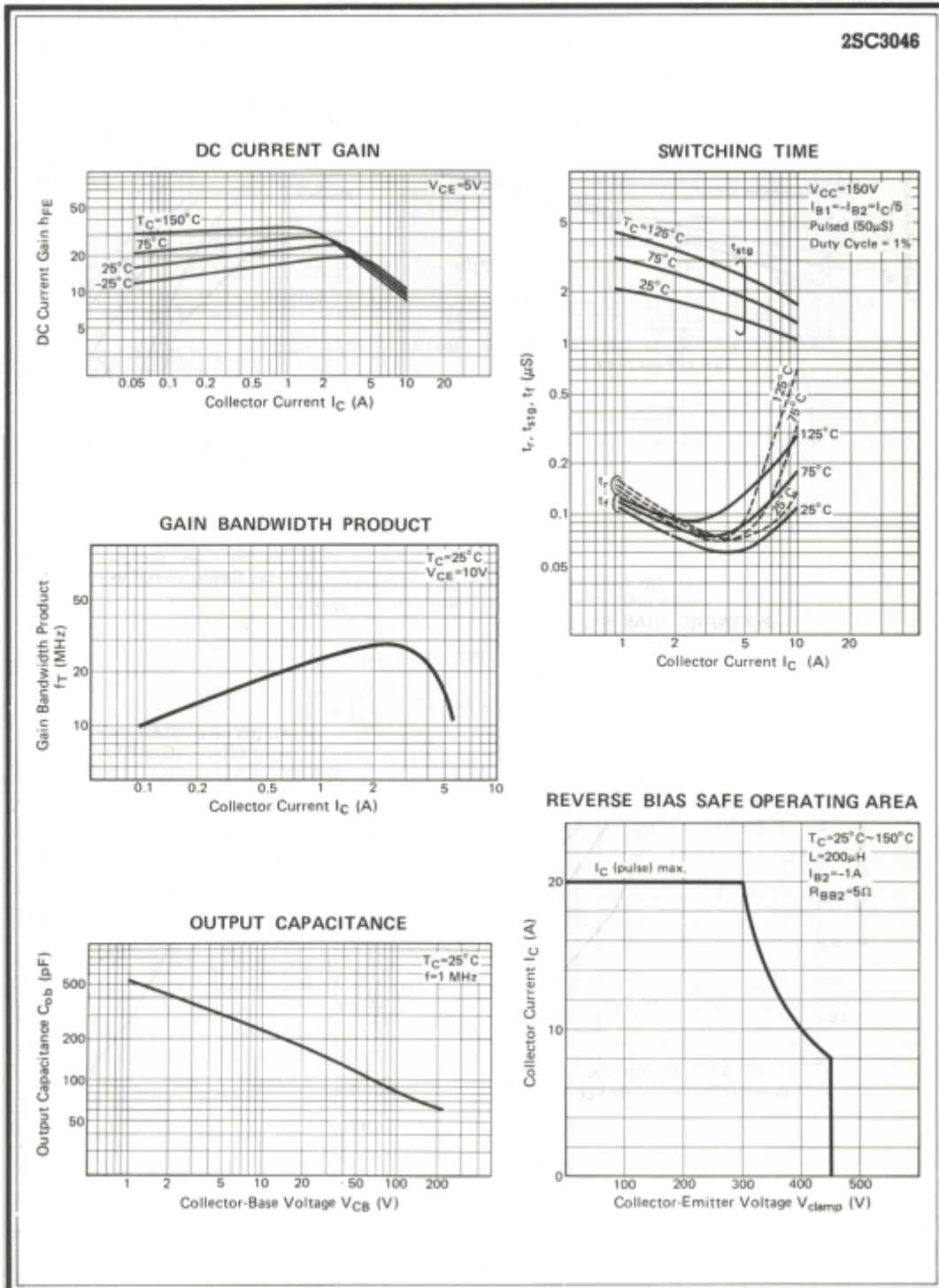
**ELECTRICAL CHARACTERISTICS** ( $T_a = 25^\circ\text{C}$ )

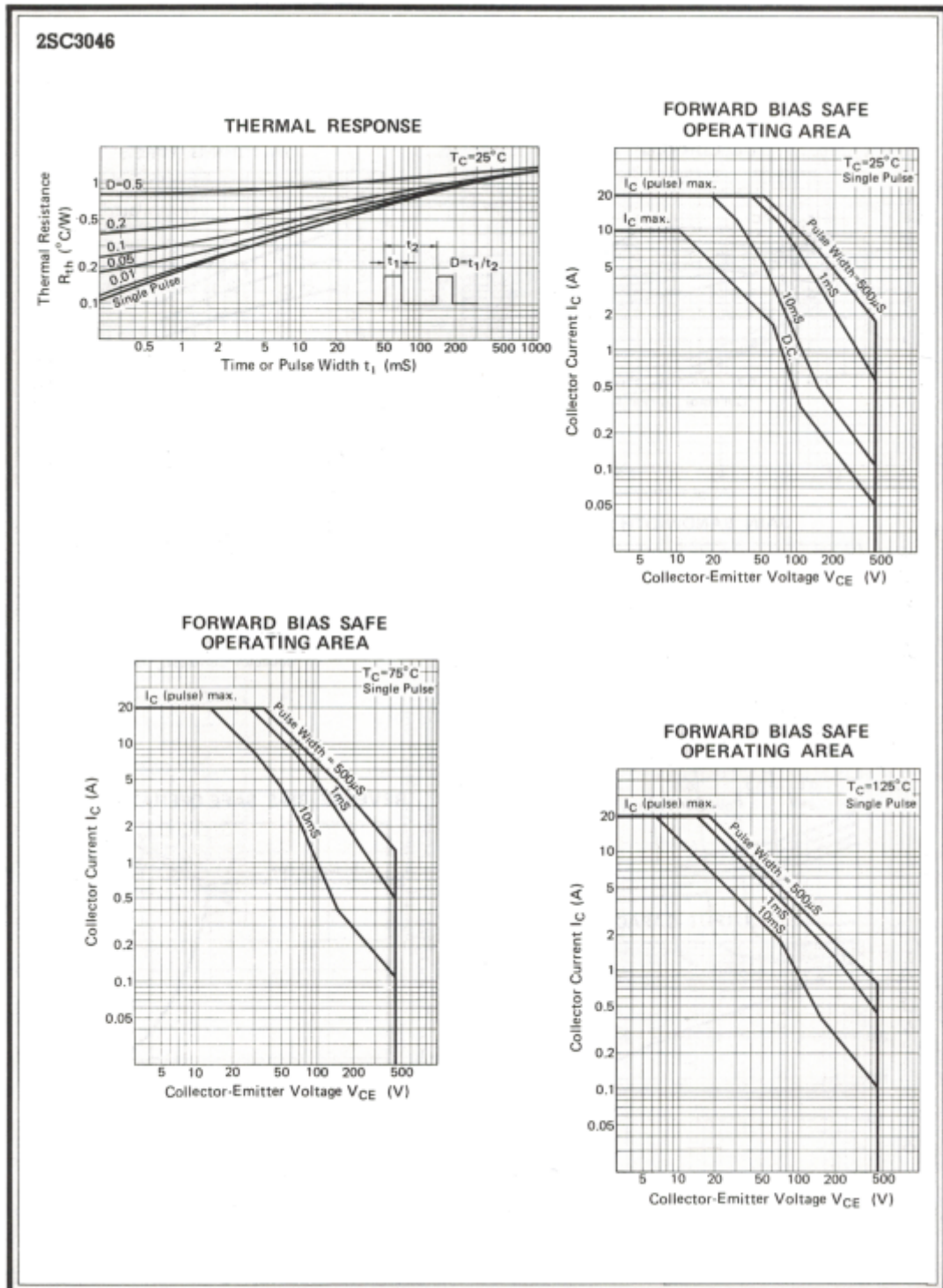
Parameter	Symbol	Test Conditions	Limits			Unit
			Min.	Typ.	Max.	
Collector to Base Breakdown Voltage	$V_{(BR)CBO}$	$I_C = 1\text{mA}$ , $I_E = 0$	600	—	—	V
Emitter to Base Breakdown Voltage	$V_{(BR)EBO}$	$I_E = 1\text{mA}$ , $I_C = 0$	7	—	—	V
Collector to Emitter Sustaining Voltage	$V_{CEO(sus)}$	$I_C = 0.8\text{A}$ , $R_{BE} = \infty$	450	—	—	V
Collector to Emitter Sustaining Voltage	$V_{CEX(sus)}$	$I_C = 8\text{A}$ , $I_{B2} = -1\text{A}$ , $L = 200\ \mu\text{H}$ (*1)	450	—	—	V
Collector Cutoff Current	$I_{CBO}$	$V_{CB} = 500\text{V}$ , $I_E = 0$	—	—	100	$\mu\text{A}$
Collector Cutoff Current	$I_{CBO}$	$V_{CB} = 500\text{V}$ , $I_E = 0$ , $T_C = 100^\circ\text{C}$	—	—	1	mA
Emitter Cutoff Current	$I_{EBO}$	$V_{EB} = 6\text{V}$ , $I_C = 0$	—	—	100	$\mu\text{A}$
DC Current Gain	$h_{FE}$	$V_{CE} = 5\text{V}$ , $I_C = 6\text{A}$ (*2)	10	14	30	—
Collector to Emitter Saturation Voltage	$V_{CE(sat)}$	$I_C = 6\text{A}$ , $I_B = 1.2\text{A}$ (*2)	—	0.43	1.0	V
Base to Emitter Saturation Voltage	$V_{BE(sat)}$	$I_C = 6\text{A}$ , $I_B = 1.2\text{A}$ (*2)	—	1.05	1.5	V
Output Capacitance	$C_{ob}$	$V_{CB} = 10\text{V}$ , $I_E = 0$ , $f = 1\text{MHz}$	—	230	—	pF
Gain Bandwidth Product	$f_T$	$V_{CE} = 10\text{V}$ , $I_C = 2\text{A}$	—	28	—	MHz
Rise Time	$t_r$	$V_{CC} = 150\text{V}$ (*1) $I_C = 6\text{A}$ , $I_{B1} = -I_{B2} = 1.2\text{A}$	—	0.08	0.3	$\mu\text{s}$
Storage Time	$t_{stg}$		—	1.25	1.5	$\mu\text{s}$
Fall Time	$t_f$		—	0.07	0.2	$\mu\text{s}$

\*1 Test Circuit \*2 Pulsed  $P_W \leq 300\ \mu\text{s}$ , Duty Ratio  $\leq 6\%$

**PACKAGE TYPE:** TO-3. See page 5-23 for dimensions.

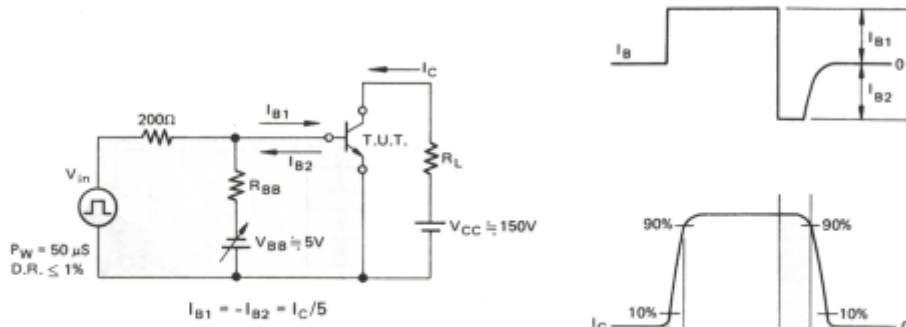




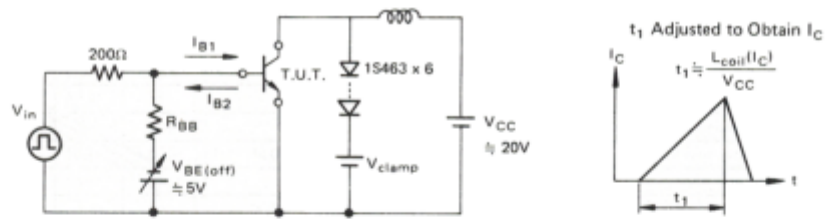


2SC3046

TEST CIRCUIT USED FOR MEASUREMENT OF SWITCHING TIME (RESISTANCE)



TEST CIRCUIT USED FOR MEASUREMENT OF  $V_{CEX(SUS)}$  AND REVERSE BIAS SAFE OPERATING AREA



- (a)  $V_{CEX(SUS)}$   
 $I_C = 8A, I_{B1} = 2A, I_{B2} = -1A, R_{BB} = 5\Omega, V_{clamp} = 450V$
- (b) Reverse Bias Safe Operating Area  
 $I_{B1} \leq 4A, I_{B2} = -1A, R_{BB} = 5\Omega$

**TRANSISTOR PACKAGING INFORMATION**

